# **Electronic Supplementary Information**

# Photoexcitation of PbS Nanosheets Leads to Highly Mobile Charge Carriers and Stable Excitons

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# 1. Evaluation of the exciton binding energy for 16 nm PbS-NSs

For 16 nm PbS-NSs, we obtain a value  $E_B = 21$  meV, by taking it as the average value between the value calculated by Yang and Wise for 8 nm thick PbS-NSs (40 meV) and the bulk value.<sup>1</sup> The latter is obtained from the relation:

$$E_B = 13.6 \ eV \cdot \frac{m^* \ 1}{m_0 \epsilon_\infty} \tag{S1}$$

where  $m^*$  is the reduced effective mass of the exciton given by  $\binom{m_e m_h}{(m_e + m_h)}$ ,  $\epsilon_{\infty}$  is the high frequency dielectric constant and  $m_0$  is the free electron mass.<sup>2</sup> From Eq. (S1), the binding energy is  $E_B = 2.7$  meV by considering  $m_e = 0.12$ ,  $m_h = 0.11$  and  $\epsilon_{\infty} = 17.^3$ 

# 2. Number of absorbed photons per NS

The number of absorbed photons per unit area in a single nanosheet is calculated as:

$$N_a^{NS} = \frac{N_a}{n_{NS}},$$

where  $N_a$  is the absorbed photoexcitation density in the NS-film (absorbed photons per unit area) and  $n_{NS}$  is the number of NS within the film, which is evaluated by determining the film thickness (see Experimental Section of the main manuscript) and the thickness of a single NS.

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# 3. Fits of the THz response in the frequency domain



Fig. S1. Fits of the THz response at 8 ps for PbS-NSs with different thickness (indicated at the top of panels). In the right panels the total response (same color as the sample), EX response (yellow) and free charge carrier response (magenta) from fits are shown in a wider frequency range. Note that with obtained  $a_B$  values the response of more than 70 % of photogenerated charge carriers at t = 8 ps is weak.



Fig. S2. Fits of the THz response at 200 ps for PbS-NSs with different thickness (indicated at the top of panels). In the right panels the total response (same color as the sample), EX response (yellow) and free charge carrier response (magenta) from fits are shown in a wider frequency range.



#### 4. Normalized THs response at 8 and 200 ps

Fig. S3. Comparison of normalized THz spectra at 8 and 200 ps after photoexcitation, showing that the later time response can be described by a scaling factor. In the main manuscript, this is related to the reduction of the fraction of free charge carriers only.



# 5. Fits of the THz response by considering free charge carriers only

Fig. S4. An attempt for fitting the measured data by considering free charge carriers only and the Drude-Smith model. The response is well reproduced for the 16 and 4 nm samples, while a noticeable disagreement is apparent for the imaginary component of 6 nm thick PbS-NSs. Obtained effective masses deviate substantially from values reported in the main manuscript.

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- 3. I. Kang and F. W. Wise, J. Opt. Soc. Am. B, 1997, 14, 1632-1646.